# DEPARTMENT OF ELECTRONICS AND COMMUNICATION ENGINEERING

## NATIONAL INSTITUTE OF TECHNOLOGY, TIRUCHIRAPPALLI

COURSE PLAN – PART I				
Course Title	VLSI SYSTEMS			
Course Code	ECMI25	No. of Credits	3	
Course Code of Pre- requisite subject(s)	ECMI14			
Session	Jan - 2023	Section (if, applicable)		
Name of Faculty	Dr. R. Murali krishna	Department	Electronics and communication engineering	
Email	mkr@nitt.edu	Telephone No.		
Name of Course Coordinator(s) (if, applicable)	- I			
E-mail	•	Telephone No.		
Course Type	Core course	Elective cou	Irse	
Syllabus (approved in	BoS)			
	gy, VLSI technology- NMC	DS, CMOS and BICM	OS circuit fabrication.	
Layout design rules. Stic	ck diagram. Latch up.			
Characteristics of MOS and CMOS switches. Implementation of logic circuits using MOS and CMOS technology, multiplexers and memory, MOS transistors, threshold voltage, MOS device design equations. MOS models, small-signal AC analysis. CMOS inverters, propagation delay of inverters, Pseudo NMOS, Dynamic CMOS logic circuits, power dissipation.				
Programmable logic devices- antifuse, EPROM and SRAM techniques. Programmable logic cells. Programmable inversion and expander logic. Computation of interconnect delay, Techniques for driving large off-chip capacitors, long lines, Computation of interconnect delays in FPGAs Implementation of PLD, EPROM, EEPROM, static and dynamic RAM in CMOS.				
An overview of the features of advanced FPGAs, IP cores, Softcore processors, Various factors determining the cost of a VLSI, Comparison of ASICs, FPGAs , PDSPs and CBICs . Fault tolerant VLSI architectures				
VLSI testing -need for testing , manufacturing test principles, design strategies for test, chip level and system level test techniques.				
COURSE OBJECTIVES				
To introduce various aspects of VLSI circuits and their design including testing.				
COURSE OUTCOMES (CO)				
Course Outcomes Aligned Programm Outcomes (PO)				
1. Describe the techniques used for VLSI fabrication, design of CMOS <b>PO1, PO3, PO4, PO5</b>				
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logi	c circuits, switches and me	emory		
	cribe the techniques use tches and memory in VLS	PO1, PO3, PO4, PO5		
	neralize the design techniqu SI circuits such as area, spo	PO1, PO2, PO3, PO4, PO5,PO7, PO12		
eva relia	lain and compare the arcl luate their characteristics ability. Use the advanced I ems	PO1, PO2, PO3, PO4 PO5 PO7		
5. Describe the techniques for fault tolerant VLSI circuits. Explain and compare the techniques for chip level and board level testing			PO1, PO2, PO3, PO4, PO5,PO7, PO12	
	SE OVERVIEW	COURSE PLAN – PART II		
Studen knowle	ts will be able to learn a	ledge about NMOS, BICMOS and CM bout Programmable logic devices and ementation of PLD, EPROM, EEPROM	cells. They can acquire	
S.No.	Week/Contact Hours	Торіс	Mode of Delivery	
1	Week 1 (3 contact Hours)	VLSI design methodology, VLSI technology- NMOS, CMOS and BICMOS circuit fabrication.		
2	Week 2 (3 contact Hours)	Layout design rules. Stick diagram. Latch up. Characteristics of MOS and CMOS switches.		

2	Week 2 (3 contact Hours)	Latch up. Characteristics of MOS and CMOS switches.	Lecture	
3	Week 3 (3 contact Hours)	Implementation of logic circuits using MOS and CMOS technology, multiplexers and memory,	C&T/ PPT or any suitable mode	
4	Week 4 (3 contact Hours)	MOS transistors, threshold voltage, MOS device design equations. MOS models, small-signal AC analysis.		
5	As per Academic Calender	ASSESSMENT I - 20Marks	Descriptive/Numerial (Written)	
6	Week 6	CMOS inverters, propagation delay of inverters, Pseudo NMOS,		
	(3 contact Hours)	Dynamic CMOS logic circuits, power dissipation	Lecture C&T/ PPT or any	

9	Week 8 (3 contact Hours)	Programmable inversion and expander logic. Computation of interconnect delay, Techniques for driving large off-chip capacitors, long lines,			Lecture C&T/ PPT or any suitable mode	
10	As per Academic Calender	ASSESSMENT II - 20 Marks			Descriptive/Numerical (Written)	
11	Week 10 (3 contact Hours)	-	ation of interconnec As Implementation of	-		
12	Week 11 (3 contact Hours)	EPROM, EEPROM, static and dynamic RAM in CMOS.		Lecture C&T/ PPT or any suitable mode		
13	Week 12 (3 contact Hours)	An overview of the features of advanced FPGAs, IP cores, Soft- core processors				
14	Week 13 (3 contact Hours)	Various factors determining the cost of a VLSI, Comparison of ASICs, FPGAs, PDSPs and CBICs Fault tolerant VLSI architectures VLSI testing -need for testing ,manufacturing test principles, design strategies for test, chip level and system level test techniques.				
16	Week 14 (3 contact Hours)					
17	Week 16	-	ND ASSESSMENT – 50 Marks		Descriptive/Numerical (Written)	
COUR	SE ASSESSMENT MET	HODS (s	shall range from 4 t	:0 6)	1	
S.No.	Mode of Assessn	nent	Week/Date	Dura	ation	% Weightage
1	Assessment I Assessment II Assessment V (CPA) End Assessment			(60 mi	nutes) 25 marks	
2				nutes)	25 marks	
СРА					nutes)	20 marks
6					inutes)	50 marks
be ass 1.	SE EXIT SURVEY (men sessed) Feedback from the stud Queries through questic	lents durii			k about t	the course shall

COURSE POLICY (preferred mode of correspondence with students, policy on attendance, compensation assessment, academic honesty and plagiarism etc.) MODE OF CORRESPONDENCE (email/ phone etc)

- All the students are advised to check their NITT WEBMAIL/group mail/suggested by the course faculty, class representative regularly. All the correspondence (schedule of classes/ schedule of assessment/ course material/ any other information regarding this course) will be done through them only.
- 2. Queries (if required) to the course teacher shall only be emailed to the email id specified by the teacher.

### ATTENDANCE

1. Attendance will be taken by the faculty in all the contact hours. Every student should try to be present in the class during these contact hours.

#### COMPENSATION ASSESSMENT

- 1. Attending all the assessments are MANDATORY for every student.
- 2. Every student is expected to score minimum 40% of the maximum mark of the class in the total assessment (1, 2, 3, 4 and 6) to pass the course. Otherwise the student would be declared fail and 'F' grade will be awarded. Further he can take up only FORMATIVE ASSESSMENT.
- 3. Those students who missed any of the continuous assessments (CAs) due to genuine reasons can appear for retest. The scores in the retest will be considered for computing marks for CA.

#### ACADEMIC HONESTY & PLAGIARISM

- 1. All the students are expected to be genuine during the course work. Taking of information by means of copying simulations, assignments, looking or attempting to look at another student's paper or bringing and using study material in any form for copying during any assessments is considered dishonest.
- 2. Tendering of information such as giving one's program, simulation work, assignments to another student to use or copy is also considered dishonest.
- 3. Preventing or hampering other students from pursuing their academic activities is also considered as academic dishonesty.
- 4. Any evidence of such academic dishonesty will result in the loss of marks on that assessment. Additionally, the names of those students so penalized will be reported to the class committee chairperson and HoD of the concerned department.
- 5. Students who honestly producing ORIGINAL and OUTSTANDING WORK will be REWARDED.

#### ADDITIONAL INFORMATION

Queries and feedback may also be emailed to the Course Faculty at mkr@nitt.edu

FOR APPROVAL **CC-Chairperson** HOD